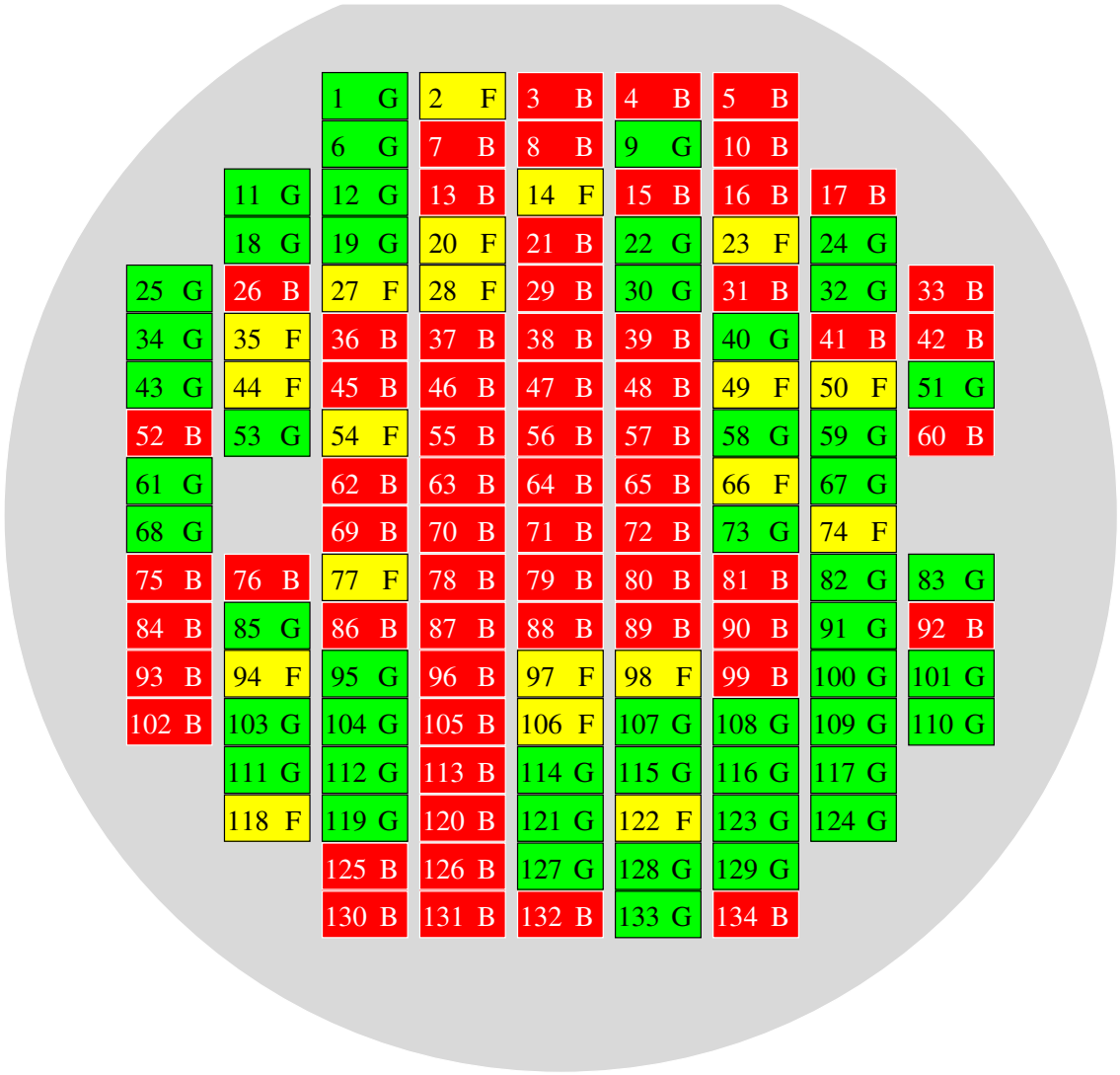
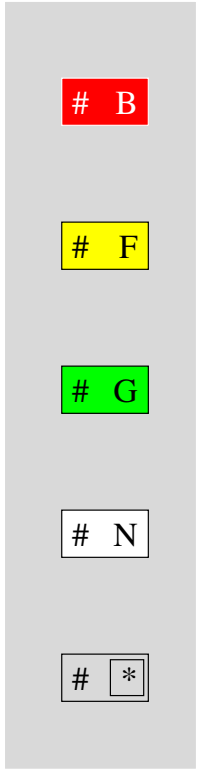
Die quality map for wafer 166 s/n: Y21316-12-08

Date: 07/01/99





Bad die

Fair die

Good die

No info

Manually tagged